

<b>Notice of References Cited</b>	Application/Control No. 10/802,580	Applicant(s)/Patent Under Reexamination FEWSTER ET AL.	
	Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

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	C	US-6,269,144 B1	07-2001	Dube et al.	378/71
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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